EEC 118 Lecture #9: Sequential Logic

Rajeevan Amirtharajah

University of California, Davis

Jeff Parkhurst

Intel Corporation

Announcements

- **Lab 4, Part 1 this week**

- **HW4 due Friday, 4PM in box, Kemper 2131**

- **Lab 3, Part 2 report due this week**

Outline

- **Review: Static CMOS Logic**

- **Finish Static CMOS transient analysis**

- **Sequential MOS Logic Circuits: Rabaey, 7.1-7.3 (Kang & Leblebici, 8.1-8.5)**

- **Next Topic: Logical Effort**

Sequential Logic Basic Definition

- **Combinational circuits' output is a function of the circuit inputs and a delay time**

  - Examples: NAND, NOR, XOR, adder, multiplier

- **Sequential circuits' output is a function of the circuit inputs, previous circuit state, and a delay time**

  - Examples: Latches, flip-flops, FSMs, pipelined adders and multipliers, microprocessors

  - Sequential elements are critical to implementing techniques such as feedback or blocks such as memory
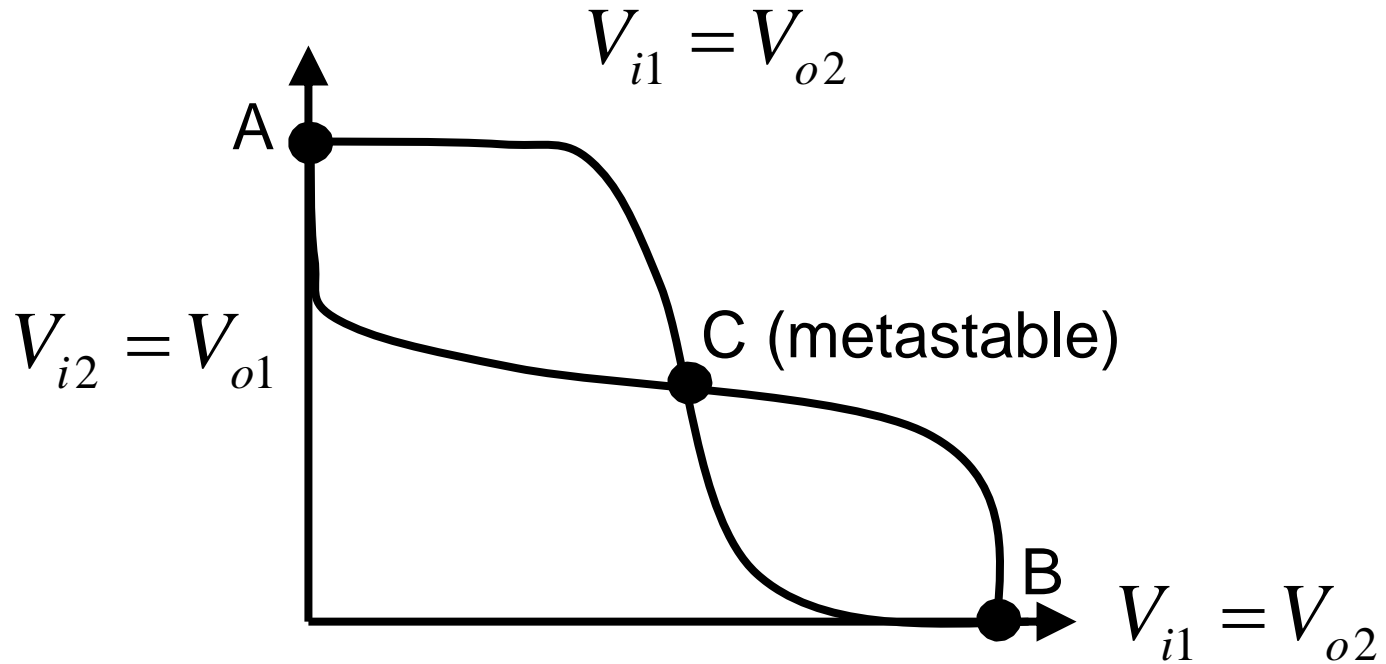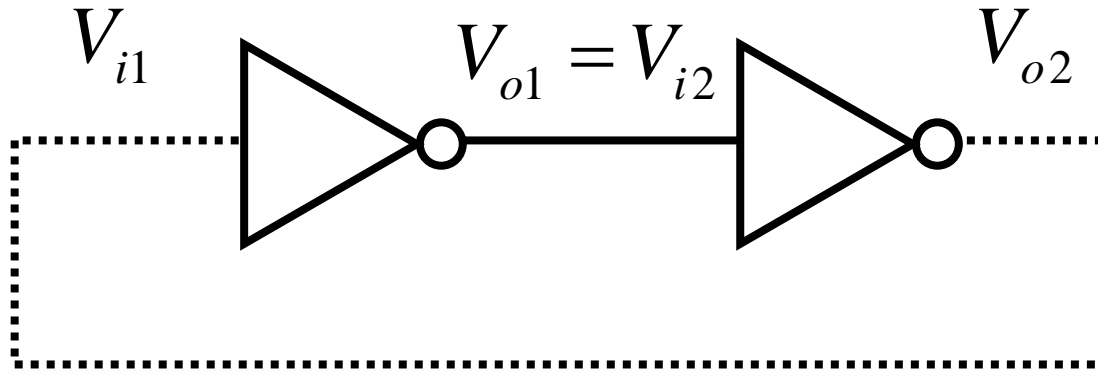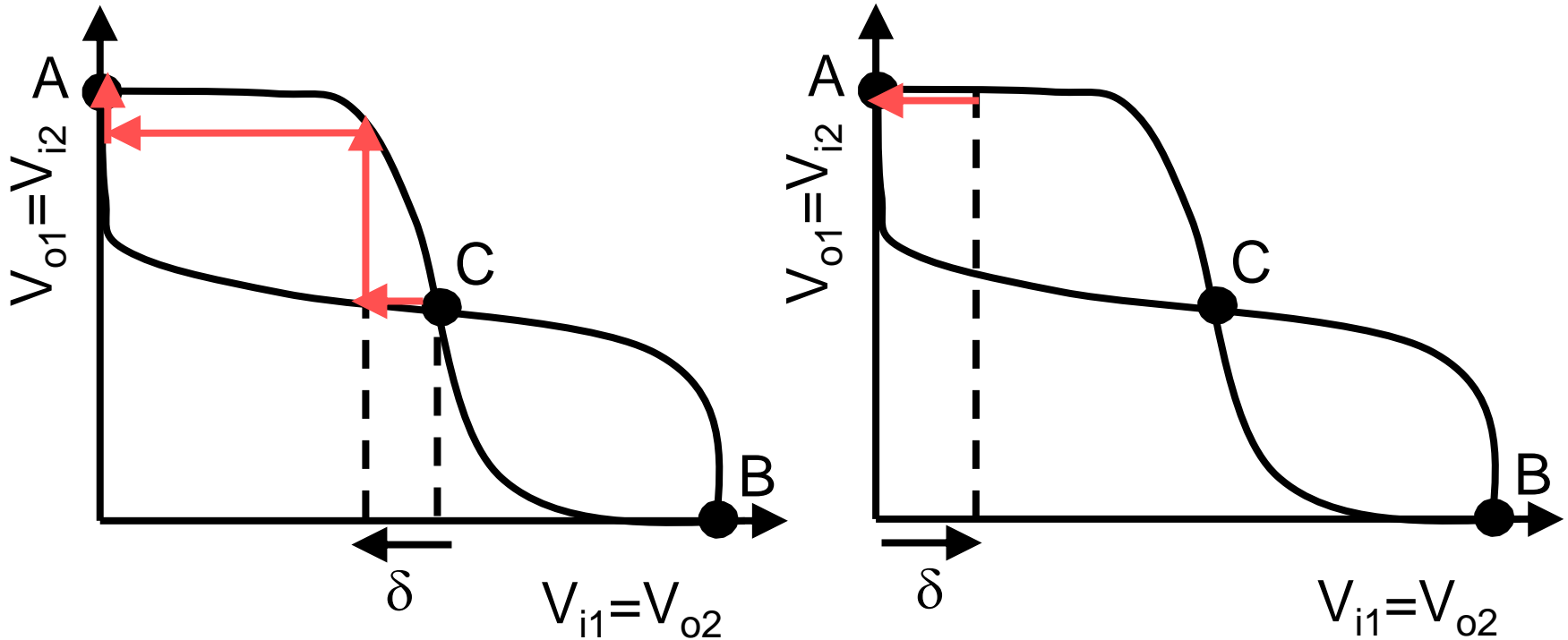
Sequential Logic Example: Mealy FSM

In ———→ LOGIC $t_{p,comb}$ ———→ Out

Φ
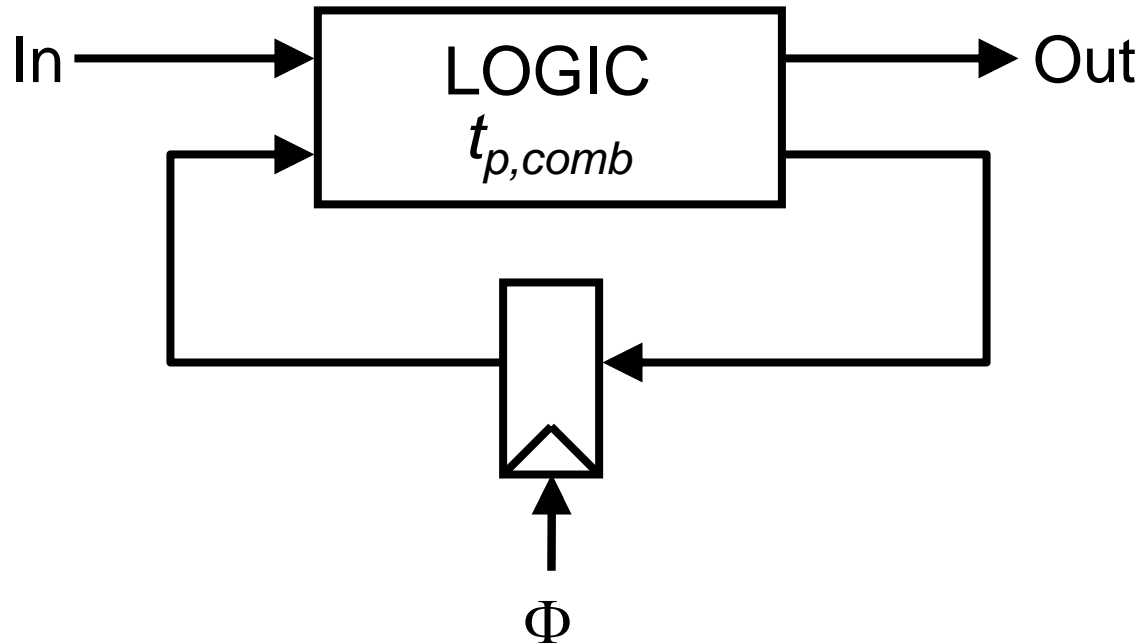
- **Two information storage mechanisms**

  – Positive feedback-based (static) circuits

  – Charge storage-based (dynamic) circuits

- **Clock signal Φ controls timing of state (memory) updates**

Positive Feedback: Bistability

$$V_{i1} \qquad V_{o1} = V_{i2} \qquad V_{o2}$$

$$V_{i1} = V_{o2}$$

A

C (metastable)

$$V_{i2} = V_{o1}$$

B

$$V_{i1} = V_{o2}$$

Metastability

Gain should be larger than 1 in the transition region
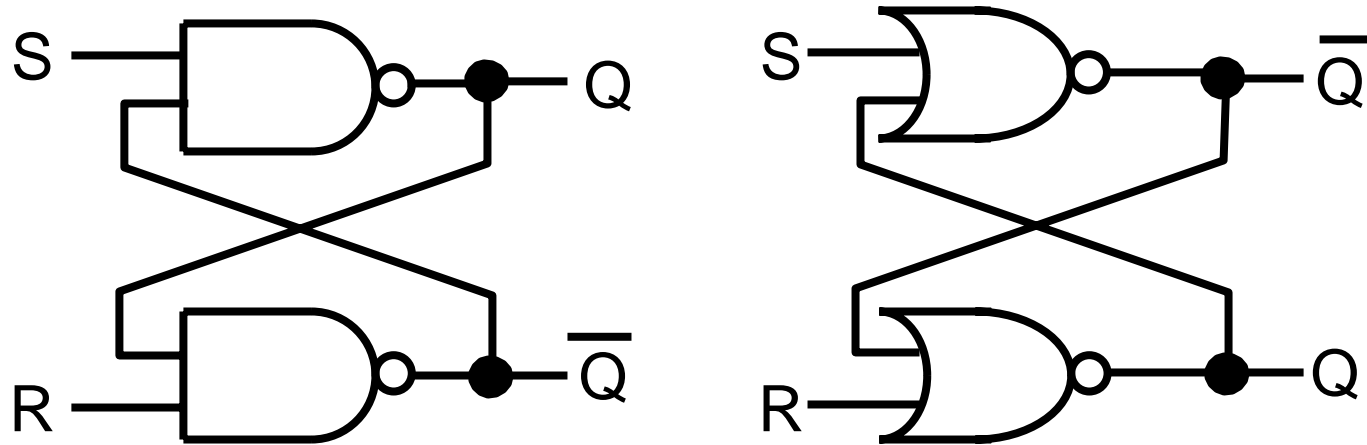
Bistable Elements

- **Bistable elements have two stable states or operation modes**

- **Cross-coupled inverters are the most basic bistable element**

  - Circuit forms the basis of latches and SRAM memory

  - Stable points on the VTC are those with the lowest energy

  - Points with high energy are unstable, perturbations are amplified
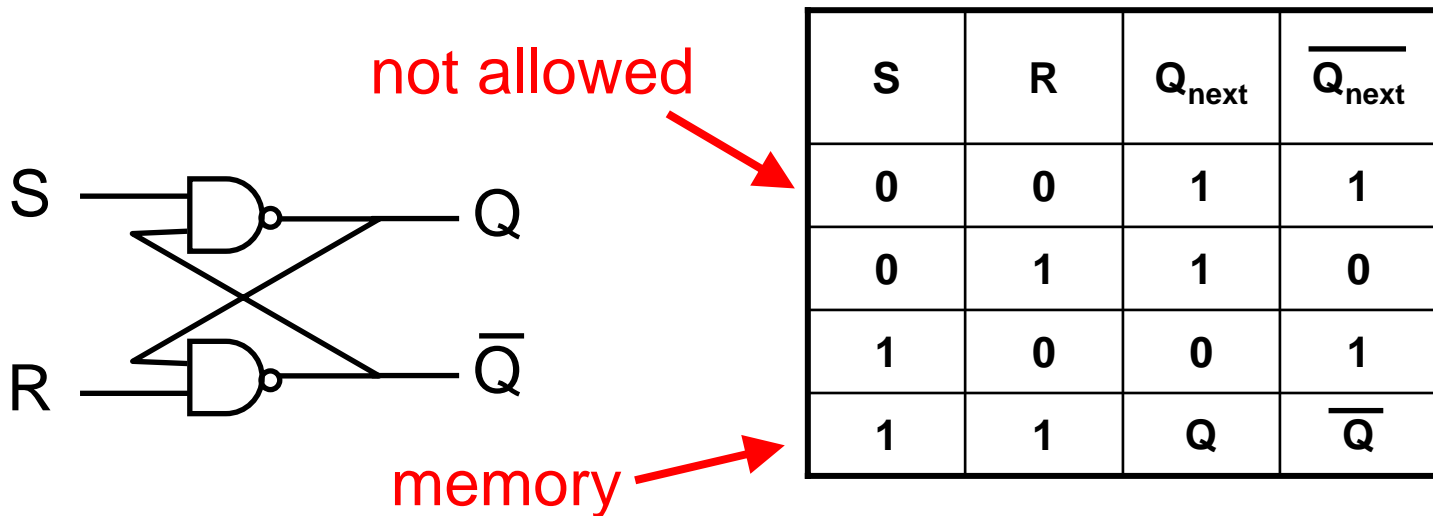
Set-Reset (SR) Latch

- **Change inverters to NAND or NOR gates, with second inputs = S(set) and R(reset)**

- **Allows control of the state of the bistable element**

- **One input state is not allowed**

- **Gating S and R with the clock prevents the latch from responding except during one phase of the clock cycle**

SR Latch

- **Sequential circuits: circuits which "store state": circuits with memory elements**

- **Latches: store previous output value for certain input combinations**

- **SR latch (NAND-based):**

not allowed

memory

S	R	Q_{next}	$\overline{Q_{next}}$
0	0	1	1
0	1	1	0
1	0	0	1
1	1	Q	$\overline{Q}$

Other Latches

- **Clocked SR latch**

  - Adds clock input. Latch output can only be set/reset when clk=1 (or clk=0)

- **Other latch types:**

  - JK latch: Removes "not allowed" state – e.g., toggles when inputs are both 1

  - T latch: Toggles when T input = 1
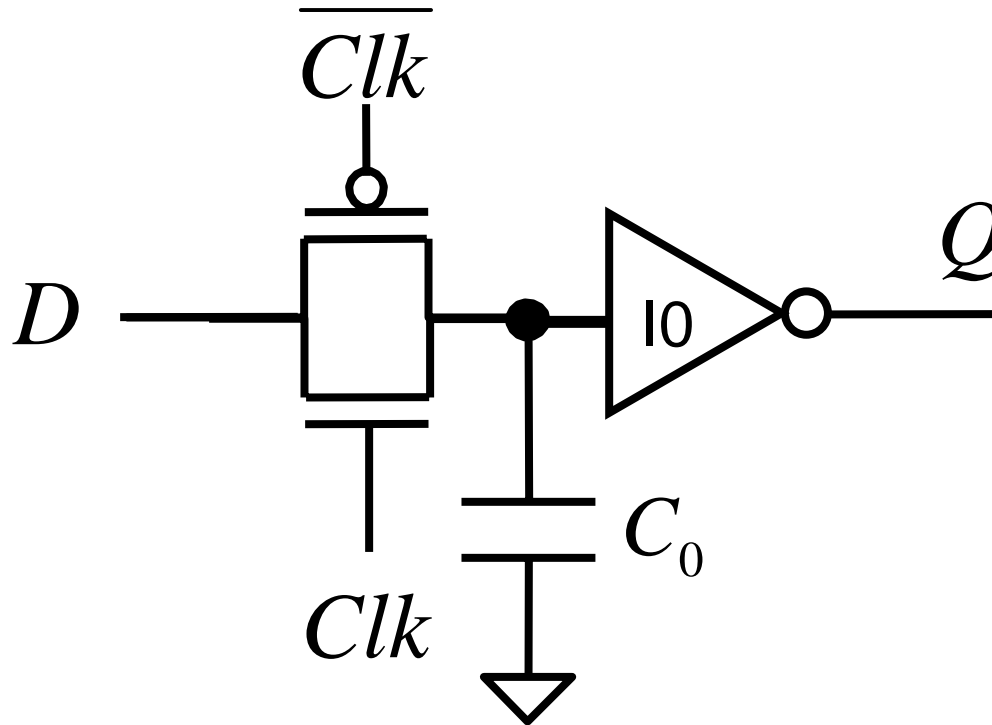
  - D latch: Output = D input

Latch Circuits

- **Many methods for implementing latches**

  – Standard CMOS gates (cross-coupled NAND, etc)

  – Transmission gates

  – Tri-state inverters

tri-state inverter

$\overline{en}$

A ——————— F

en
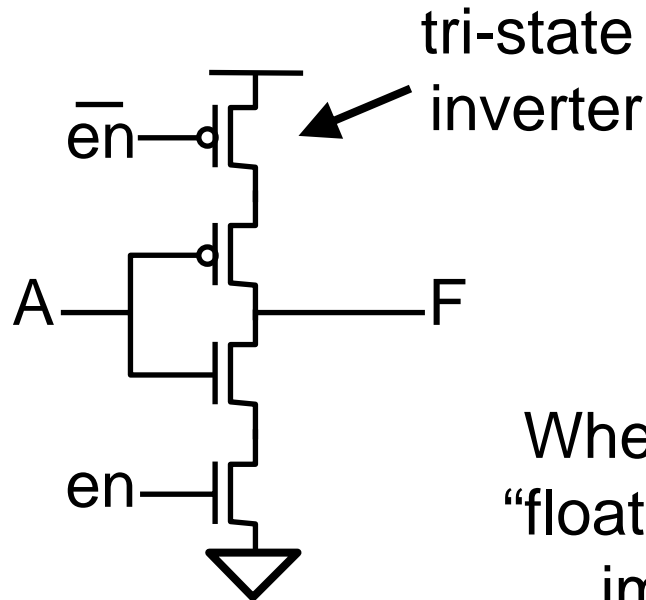
When en=0, F is "floating", i.e. high impedance

Positive Dynamic Transmission Gate Latch

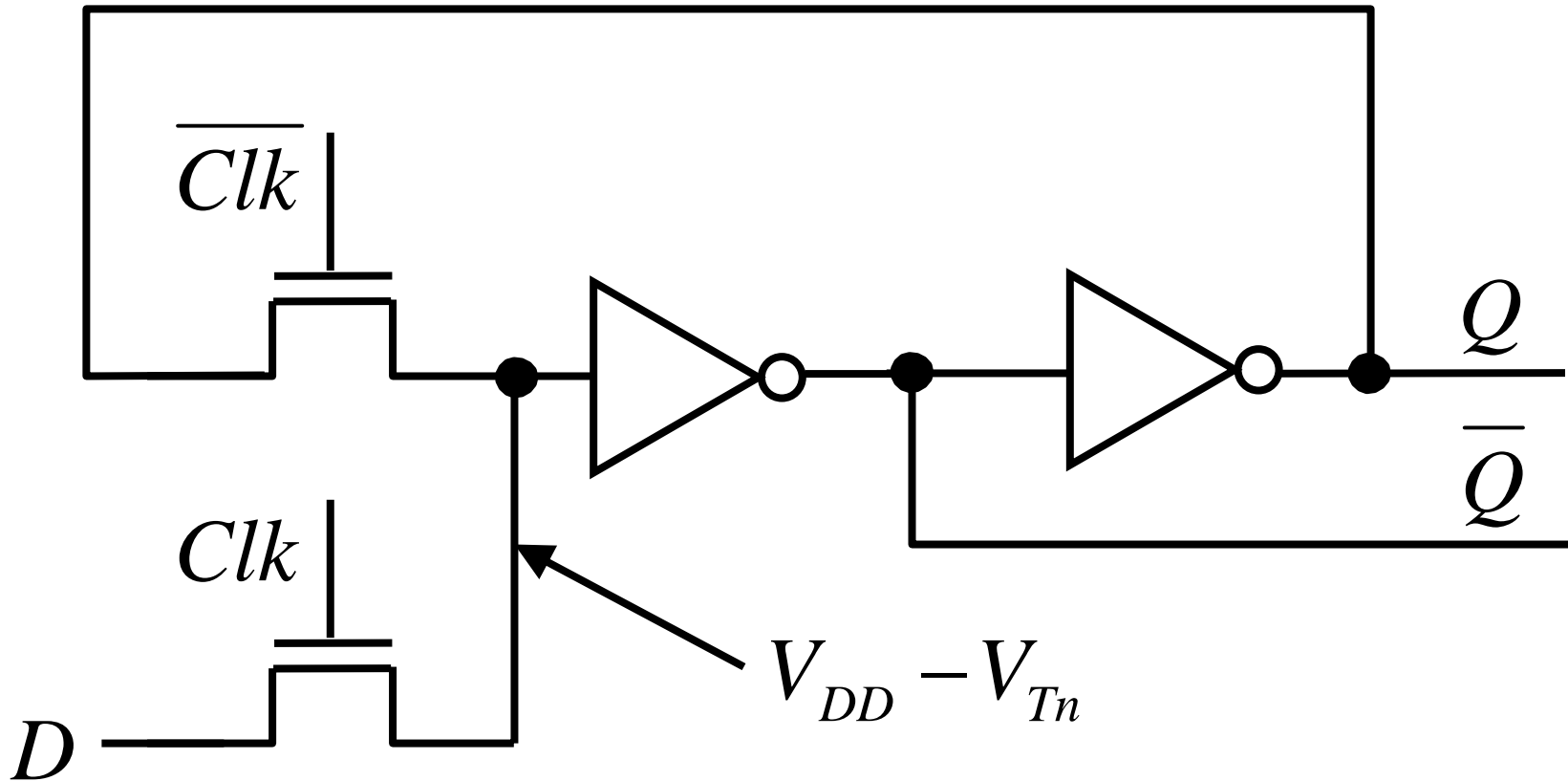$$\overline{Clk}$$

D I0 Q

Clk

C_0

- **No feedback devices**
- **Data stored on input capacitance of inverter I0**
- **Dynamic logic issues apply: leakage, capacitive coupling, charge sharing**

Transmission Gate Positive Static Latch
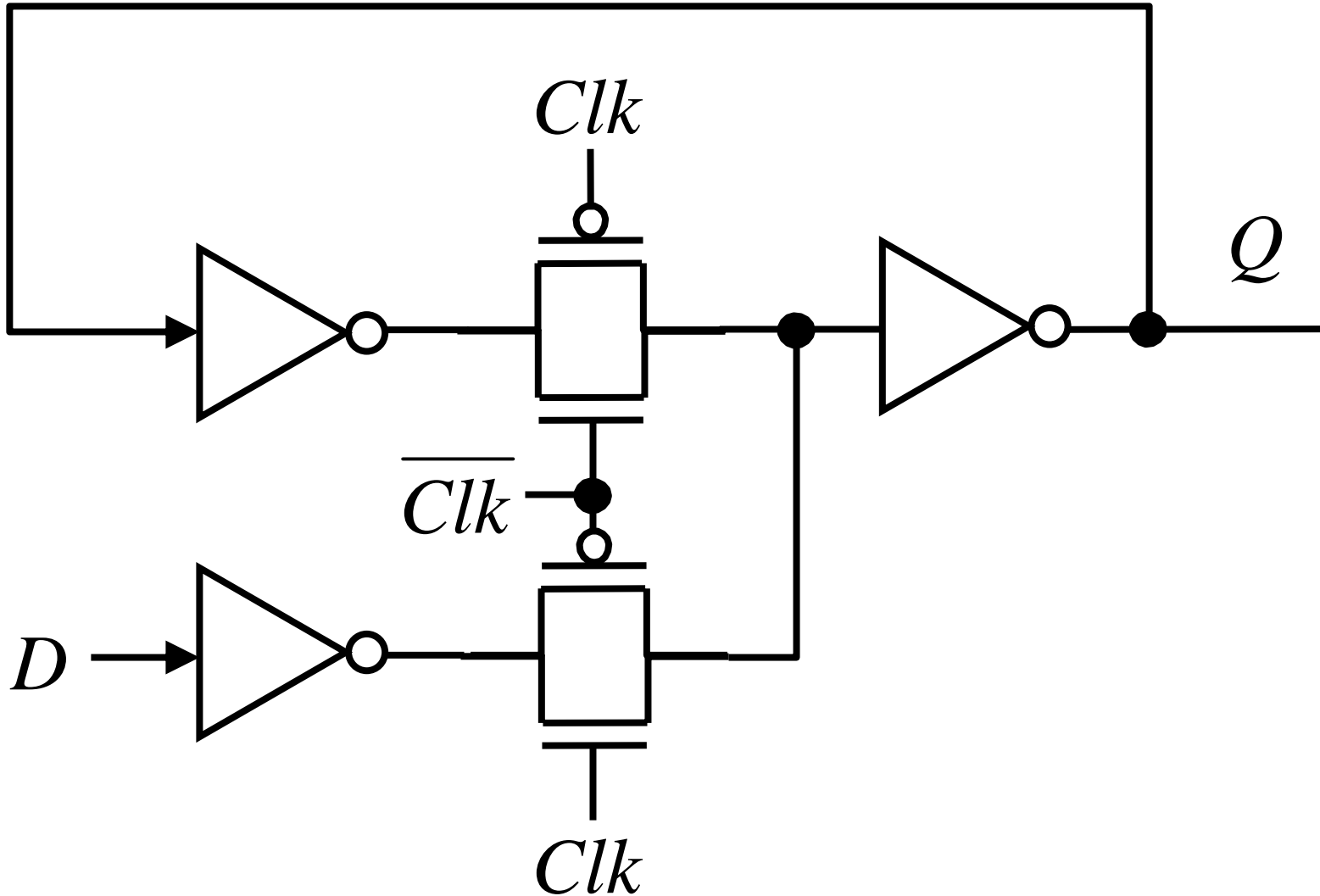
NMOS Pass Gate Positive Static Latch

- **Fewer devices, less area, lower clock load**
- **Threshold drop on internal nodes implies more static power, less noise margin**

Master-Slave Flip-Flop

- **By cascading two level-sensitive latches, one type of edge triggered flip-flop is created**

- **JK latch can be used for first stage so that no input combinations are invalid**

- **SR latch is then used for the second stage because inputs cannot be invalid**

- **Rather than using logic gate-based latches, can cascade latches such as above (e.g., transmission gate dynamic or static latches)**

Edge-Triggered Flip-Flops

- **Types of latches/flip-flops:**

  - *Level-sensitive*: output is set when clock is a certain level (0 or 1)

  - *Edge-triggered*: output can only be set on a clock edge (rising or falling)

- **Advantages of edge-triggered flip-flops:**

  - Data only needs to be stable at clock edge

  - Reduces *race conditions*: potential errors where an input data change travels through multiple latches during their "transparent" phase

Dynamic Positive Edge-Triggered FF
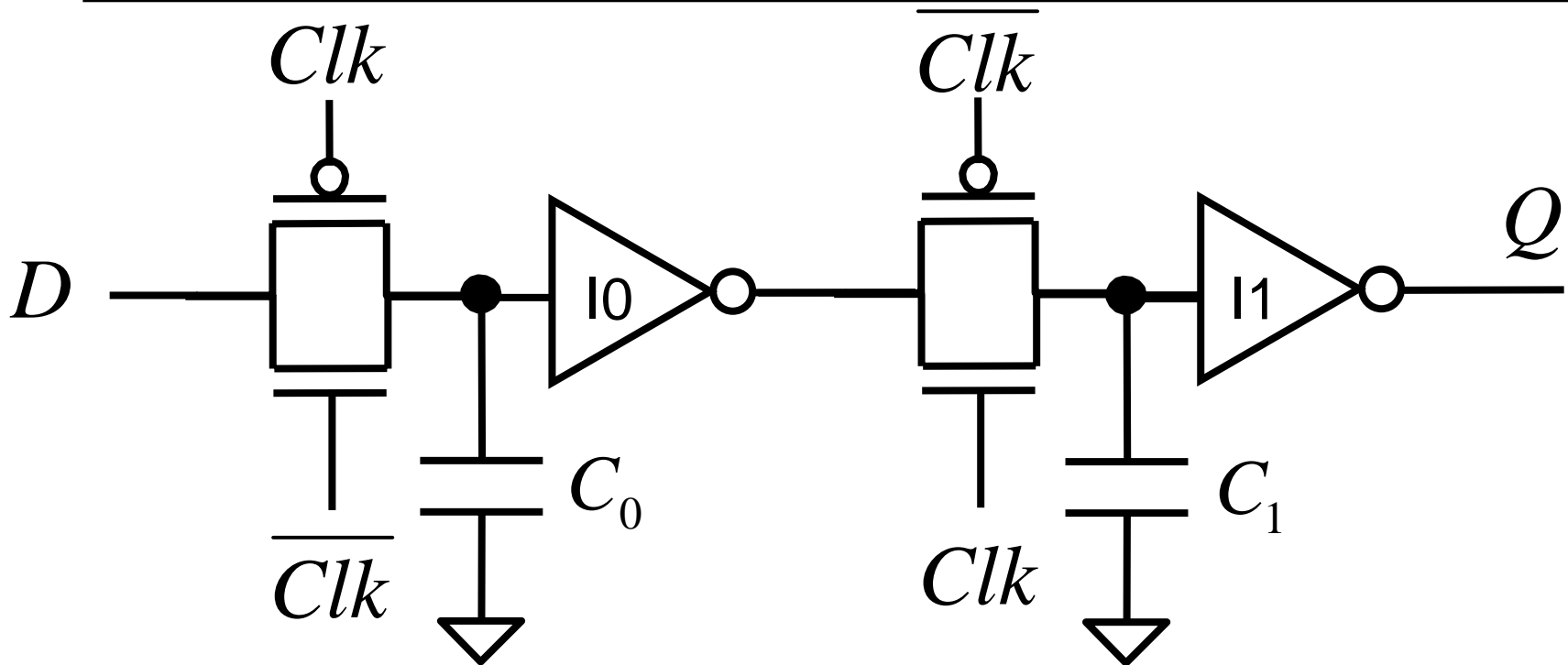
- **No feedback devices**
- **Data stored on input capacitances of inverters I0 and I1**
- **Dynamic logic issues apply: leakage, capacitive coupling, charge sharing**

Clocked Circuit Timing

- **Timing definitions:**

  - Clock-to-Q or Propagation Delay (t_{clkQ}): delay of flip-flop from clock edge to output Q

  - Setup Time (t_{setup}): amount of time *before* clock edge that data has to be stable. If data arrives after this time, it will not be latched correctly.

  - Hold Time (t_{hold}): amount of time *after* clock edge that data has to be stable.

- **It is possible to trade off setup and hold time with flip-flop circuit design**

  - Modify data and clock timing relationship by delaying one of the two signals
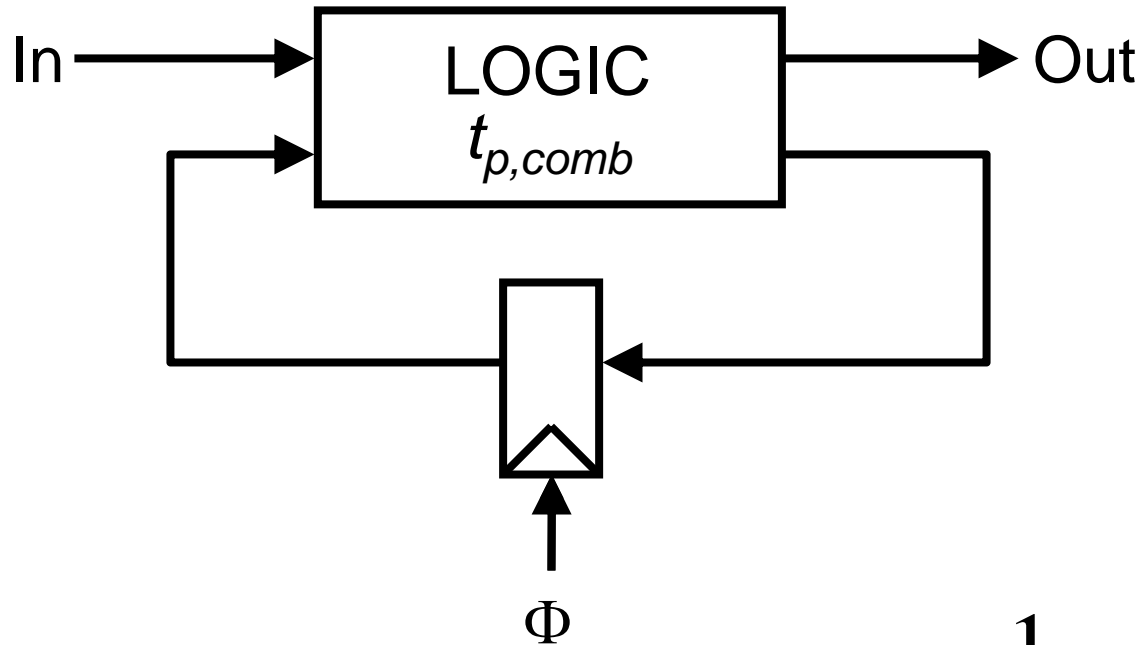
Flip-Flop: Timing Definitions
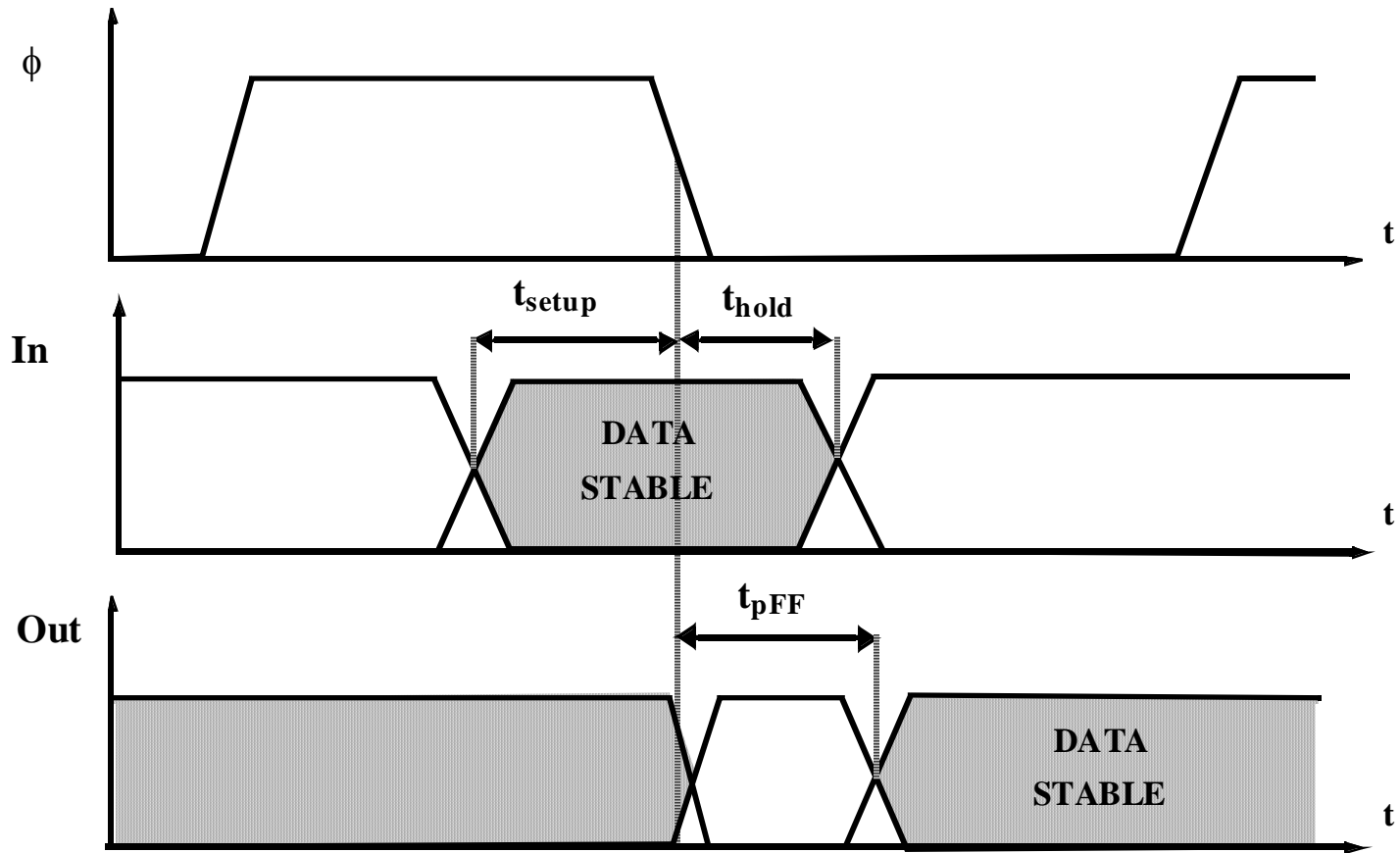
From Digital Integrated Circuits – Jan Rabaey Notes

Maximum Clock Frequency
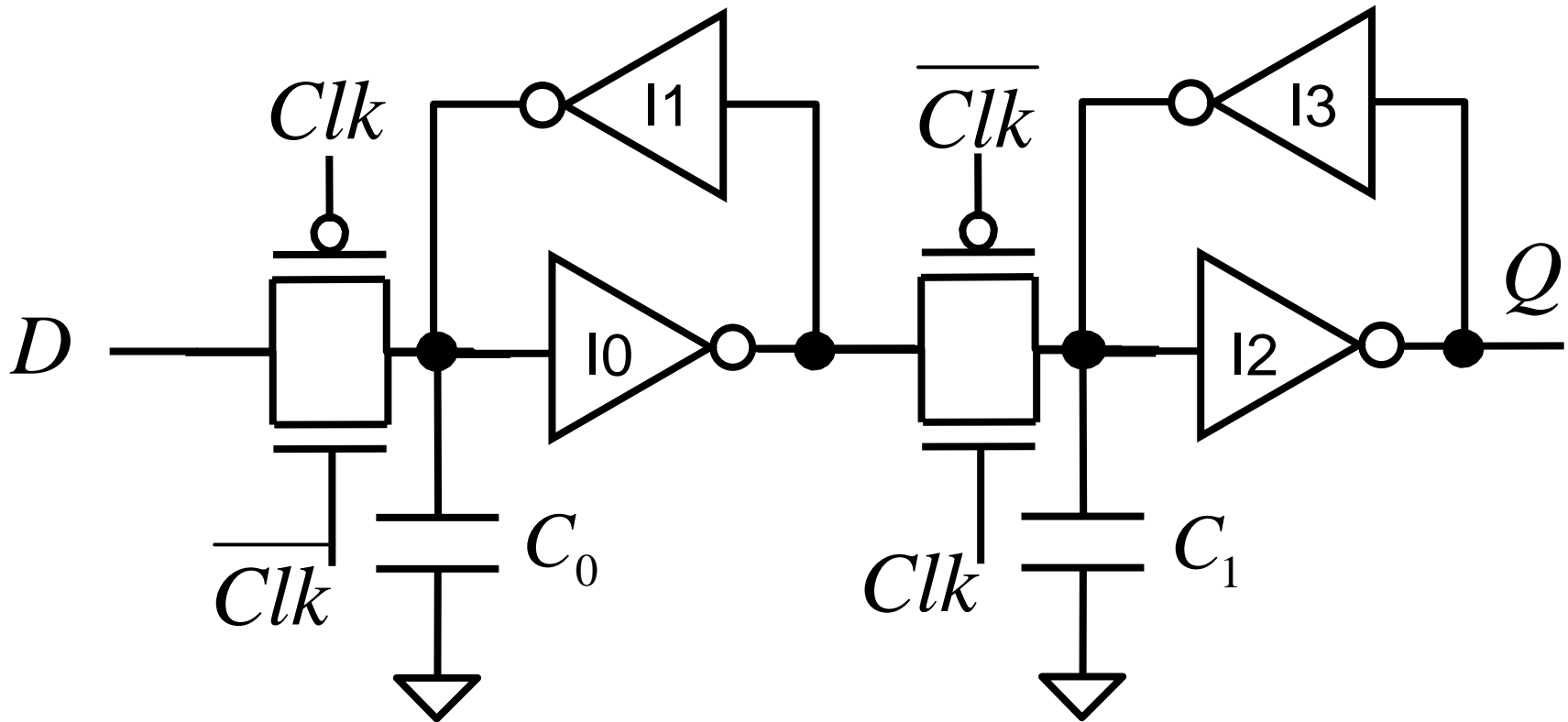
In ⟶ **LOGIC** $t_{p,comb}$ ⟶ Out

Φ

$$t_{pFF} + t_{p,comb} + t_{setup} < T = \frac{1}{f}$$

- **Signals must propagate out of flip-flop, through combinational logic, and be stable before next clock edge (clock period = T, clock frequency = f)**
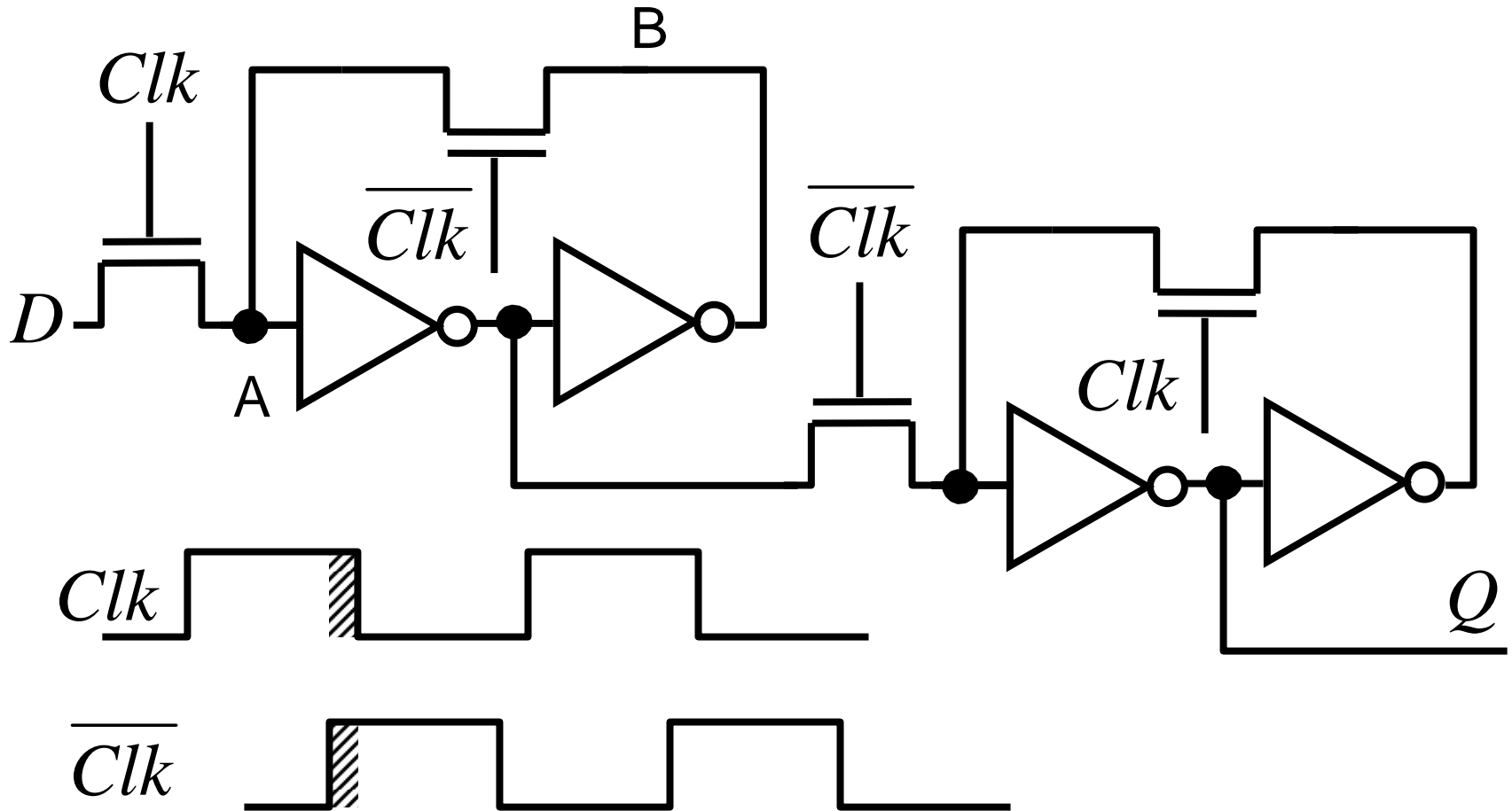
Staticized Dynamic Positive Edge-Triggered FF

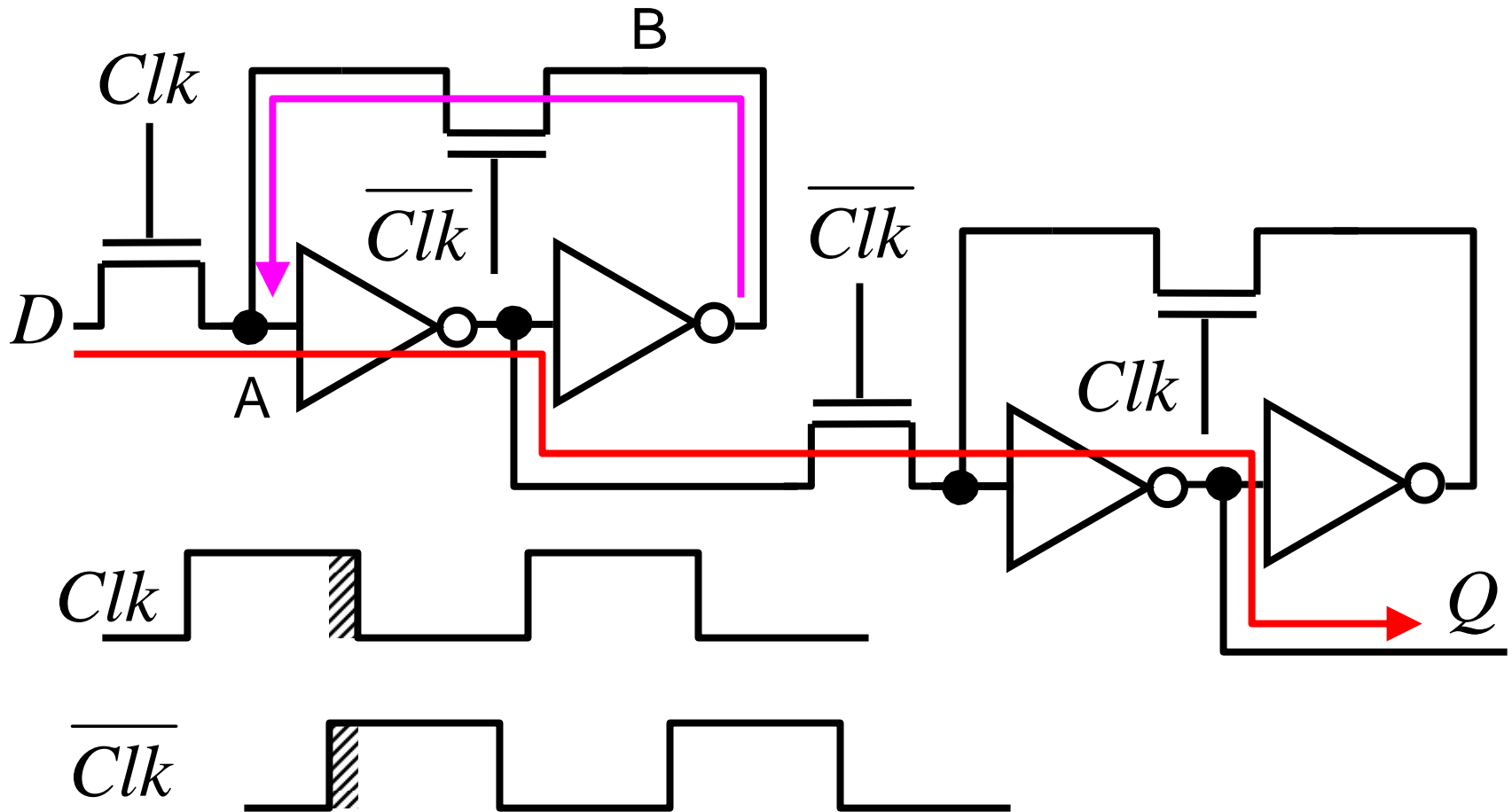- **Use weak feedback inverters to enhance robustness**
- **Returns to reduced clock load static flip-flop with same sizing issues**

Clock Overlap Failures

1. **Both high simultaneously, race condition from *D* to *Q***
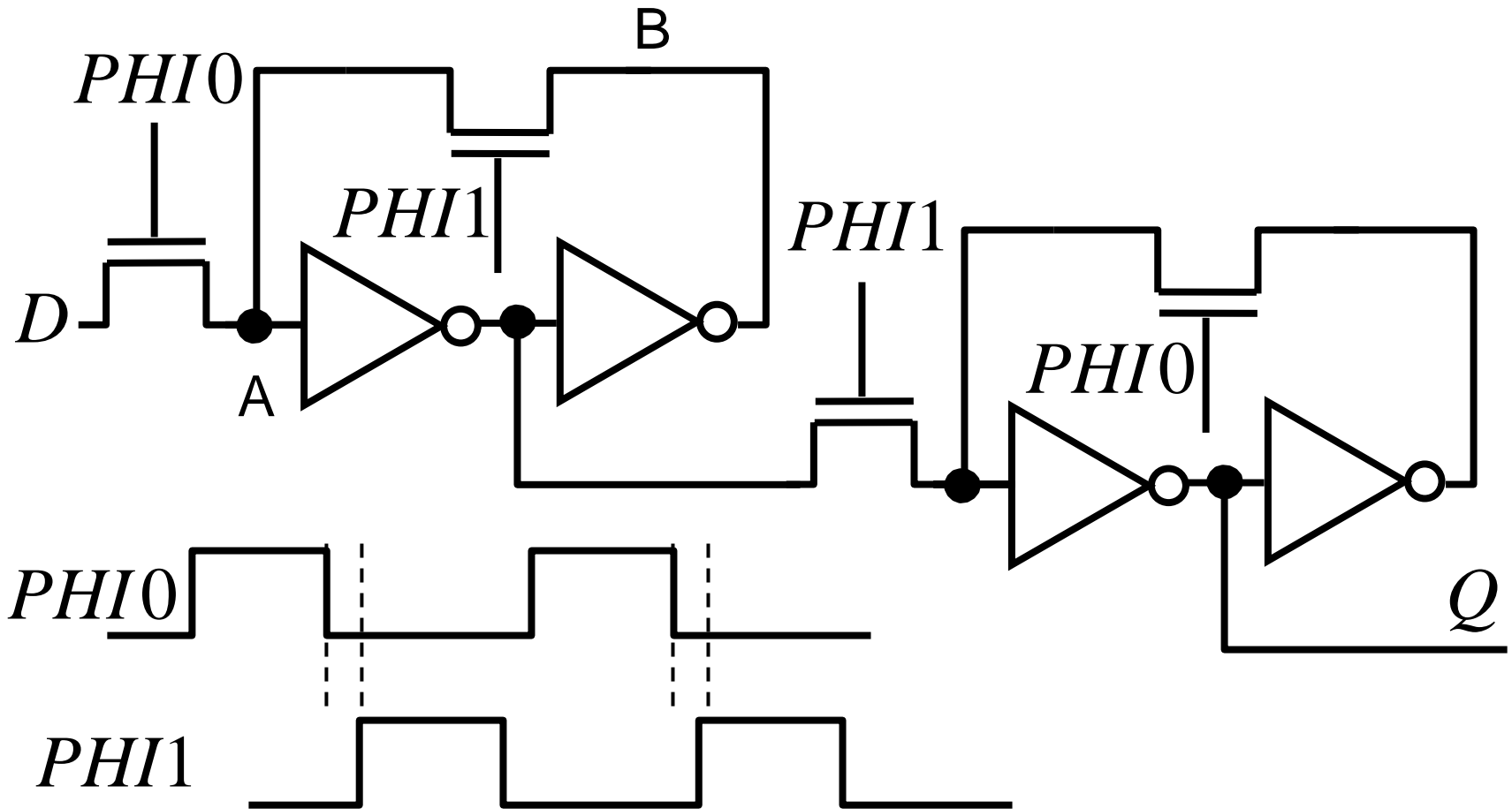2. **Node A can be driven simultaneously by *D* and B**

Race Through and Feedback Paths

1. **Both high simultaneously, race condition from *D* to *Q***
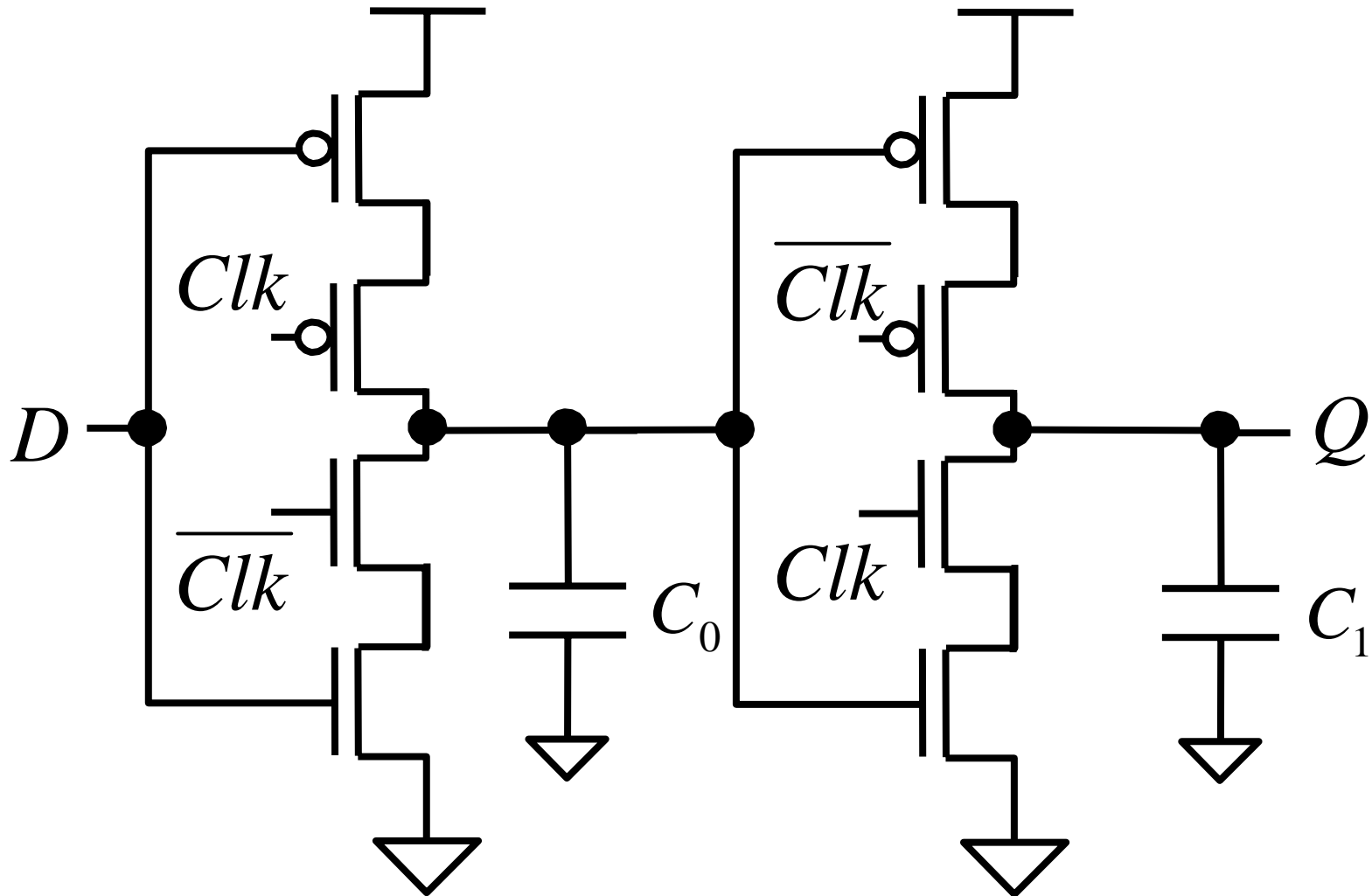2. **Node A can be driven simultaneously by *D* and B**
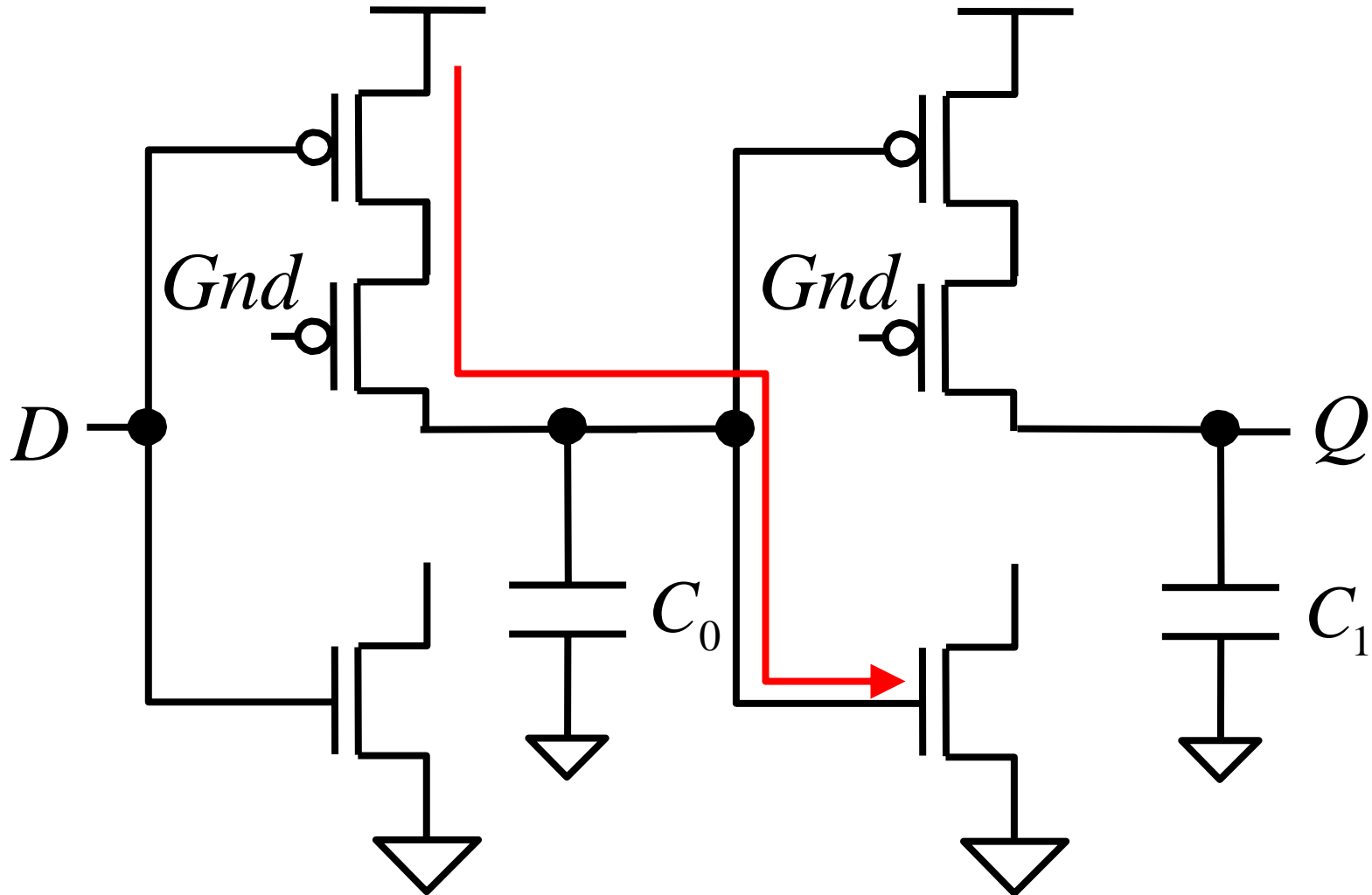
Nonoverlapping Clocks Methodology

- **Guarantee nonoverlap period long enough**
- **Note: internal nodes left high Z during nonoverlap**

C²MOS Edge Triggered Flip-Flop

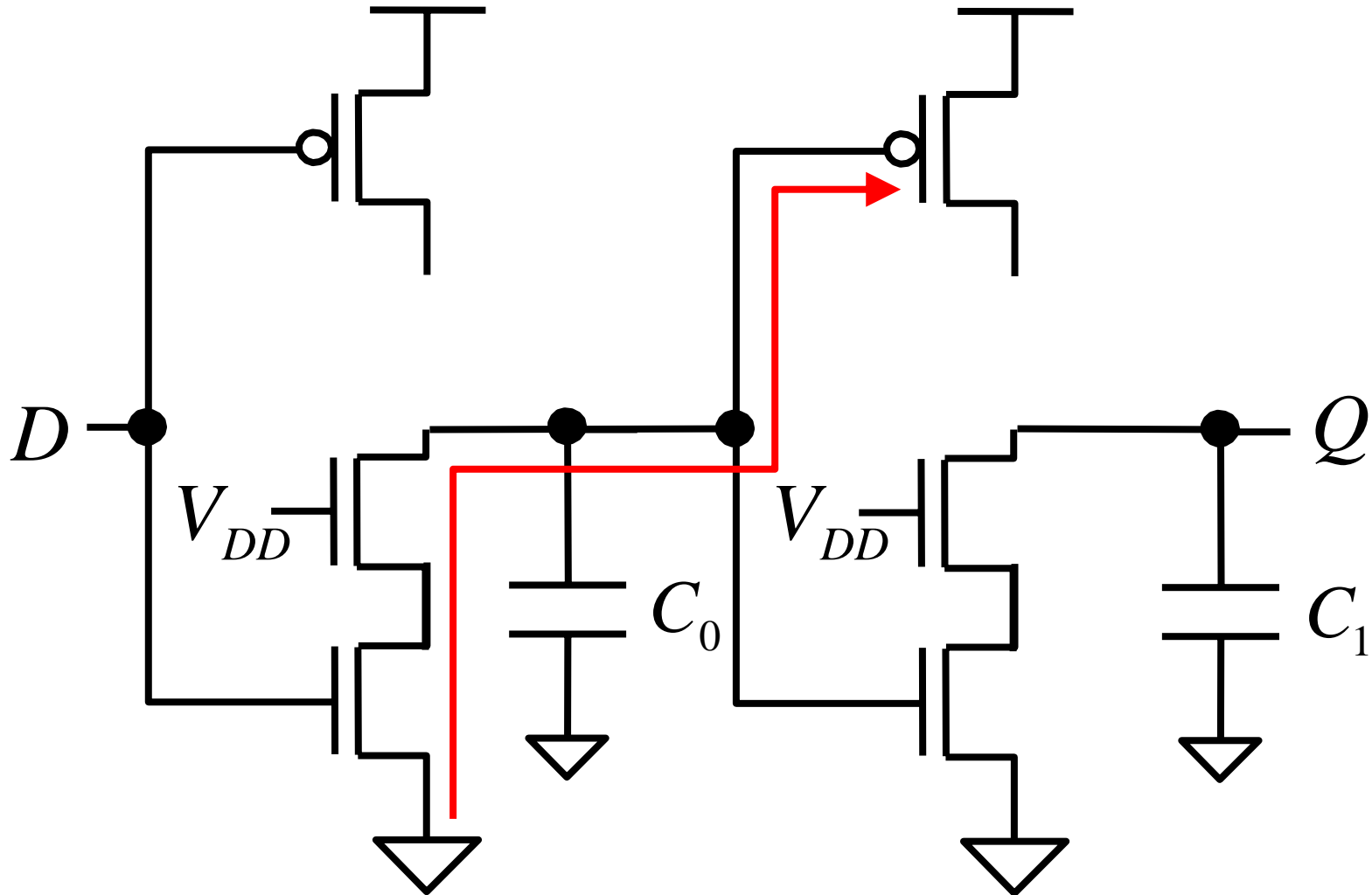- **Tristate inverters eliminate clock overlap race condition**

Clk $\overline{Clk}$ D C_0 $\overline{Clk}$ Clk C_1 Q

Zero-Zero Overlap Condition

- **Both phases low simultaneously enables opposite nets**

High-High Overlap Condition

- **Both phases high simultaneously enables opposite nets**

C²MOS Design

- **Clock overlap problems eliminated as long as rise and fall times remain fast**

  – Slow rise / fall times imply pullup and pulldown nets on simultaneously resulting in potential errors, static power

- **Dynamic flip-flop style leaves output high Z**

  – Must take care when using since output wire could be exposed to many more noise sources than internal nodes

- **Mix and match styles by using C²MOS as master and other types of latch as slave**

- **Clock load small, but potentially larger than transmission gate dynamic latches due to PMOS sizing**

Pipelining

Non-pipelined version

Pipelined version
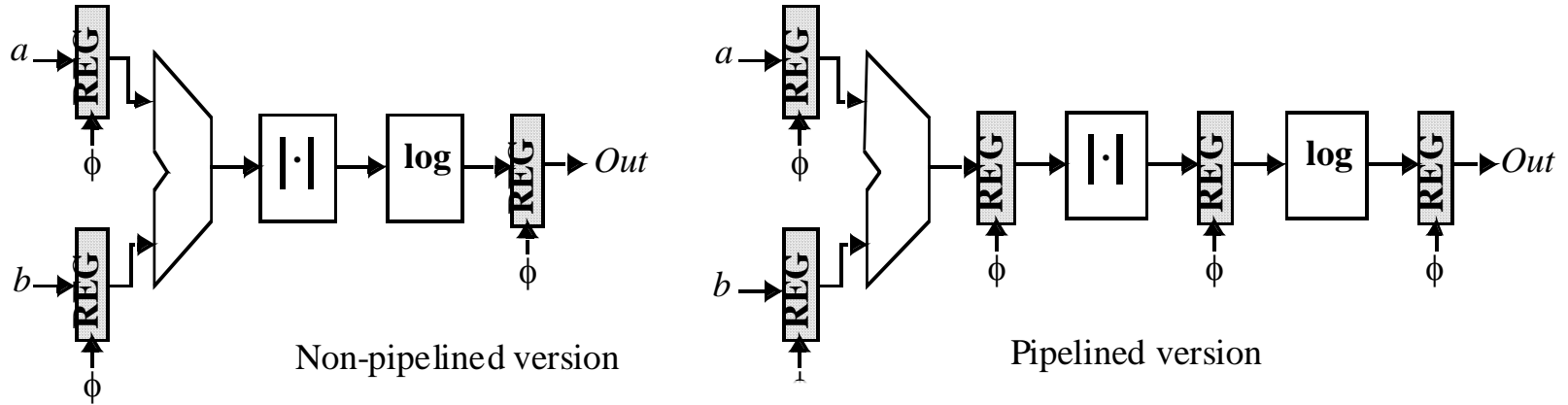
Clock Period	Adder	Absolute Value	Logarithm
1	$a_1 + b_1$		
2	$a_2 + b_2$	$|a_1 + b_1|$	
3	$a_3 + b_3$	$|a_2 + b_2|$	$\log(a_1 + b_1)$
4	$a_4 + b_4$	$|a_3 + b_3|$	$\log(|a_2 + b_2|)$
5	$a_5 + b_5$	$|a_4 + b_4|$	$\log(|a_3 + b_3|)$

From Digital Integrated Circuits – Jan Rabaey Notes

Next Topic: Logical Effort

- **Systematic method for optimizing CMOS circuits for speed**

  – Balances gate delays and logic depth

  – Enables systematic method of finding minimum sizes to achieve delay specification

  – Implicitly assumes switch RC model for propagation delay